nexperia

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023 Based on structural similarity

Supplier		User Part Number				
Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		Part Description				
		SMD package				
		Test Conditions	Duration	# Lots	# Quantity	# Rejects
			TEST			
	Pre- and Post-Stress					
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below
		JESD22-A113				
		Bake Tamb = 125 °C	24 hours			
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours			
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0
		MIL-STD-750-1				
	HTRB	M1038 Method A				
# B1	Bias	Tj = Tjmax, VR = 80 % of rated reverse voltage	1000 hours	250	11400	0
# DI	Dias	5	1000 110015	230	11400	0
		MIL-STD-750-1 M1038 Method B				
	SSOP	$T_j = T_j max$, $I_z = 100\%$ of max. datasheet				
# B1b	Steady State Operational	reverse current	1000 hours	44	1920	0
	тс	JESD22-A104				
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	311	14080	0
	UHAST	JESD22-A118				
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %	—96 hours	311	14080	0
		JESD22-A102				
	AC	Tamb = 121 °C, RH = 100 %				
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)				
		150000 4101				
	H3TRB	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of				
# A2 alt	High Humidity High Temperature Reverse Bias		1000 hours	311	14080	0
# AZ dit	remperature Reverse Dids		1000 Hours	211	14000	U
	IOL	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔT_j =				
# A5	Intermittent Operating Life	, , , ,	1000 hours	312	14120	0
			2000 110010	512	1120	~
	RSH	JESD22-A111				
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	269	8070	0
	SD					
# C10	Solderability	J-STD-002		19	6660	0

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

2,68E+09
_

© 2024 Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

nexperia.com